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REVISION HISTORY

4/16—Rev. G to Rev. H

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9/12—Rev. F to Rev. G

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 Updated Outline Dimensions 13
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3/09—Rev. E to Rev. F

Added Figure 23, Renumbered Sequentially 8
 Updated Outline Dimensions 13

5/06—Rev. D to Rev. E

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4/06—Rev. C to Rev. D

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11/95—Rev. 0: Initial Version

SPECIFICATIONS

ELECTRICAL CHARACTERISTICS

At $V_S = \pm 15\text{ V}$, $T_A = 25^\circ\text{C}$, unless otherwise noted.

Table 1.

Parameter	Symbol	Test Conditions/Comments	OP177F			OP177G			Unit
			Min	Typ	Max	Min	Typ	Max	
INPUT OFFSET VOLTAGE	V_{OS}		10	25		20	60		μV
LONG-TERM INPUT OFFSET ¹ Voltage Stability	$\Delta V_{OS}/\text{time}$			0.3			0.4		$\mu\text{V}/\text{mo}$
INPUT OFFSET CURRENT	I_{OS}			0.3	1.5		0.3	2.8	nA
INPUT BIAS CURRENT	I_B		-0.2	+1.2	+2	-0.2	+1.2	+2.8	nA
INPUT NOISE VOLTAGE	e_n	$f_0 = 1\text{ Hz to }100\text{ Hz}^2$		118	150		118	150	nV rms
INPUT NOISE CURRENT	i_n	$f_0 = 1\text{ Hz to }100\text{ Hz}^2$		3	8		3	8	pA rms
INPUT RESISTANCE Differential Mode ³	R_{IN}		26	45		18.5	45		$\text{M}\Omega$
INPUT RESISTANCE COMMON MODE	R_{INCM}			200			200		$\text{G}\Omega$
INPUT VOLTAGE RANGE ⁴	IVR		± 13	± 14		± 13	± 14		V
COMMON-MODE REJECTION RATIO	CMRR	$V_{CM} = \pm 13\text{ V}$	130	140		115	140		dB
POWER SUPPLY REJECTION RATIO	PSRR	$V_S = \pm 3\text{ V to } \pm 18\text{ V}$	115	125		110	120		dB
LARGE SIGNAL VOLTAGE GAIN	A_{VO}	$R_L \geq 2\text{ k}\Omega$, $V_O = \pm 10\text{ V}^5$	5000	12,000		2000	6000		V/mV
OUTPUT VOLTAGE SWING	V_O	$R_L \geq 10\text{ k}\Omega$	± 13.5	± 14.0		± 13.5	± 14.0		V
		$R_L \geq 2\text{ k}\Omega$	± 12.5	± 13.0		± 12.5	± 13.0		V
		$R_L \geq 1\text{ k}\Omega$	± 12.0	± 12.5		± 12.0	± 12.5		V
SLEW RATE ²	SR	$R_L \geq 2\text{ k}\Omega$	0.1	0.3		0.1	0.3		$\text{V}/\mu\text{s}$
CLOSED-LOOP BANDWIDTH ²	BW	$A_{VCL} = 1$	0.4	0.6		0.4	0.6		MHz
OPEN-LOOP OUTPUT RESISTANCE	R_O			60			60		Ω
POWER CONSUMPTION	P_D	$V_S = \pm 15\text{ V}$, no load		50	60		50	60	mW
		$V_S = \pm 3\text{ V}$, no load		3.5	4.5		3.5	4.5	mW
SUPPLY CURRENT	I_{SY}	$V_S = \pm 15\text{ V}$, no load		1.6	2		1.6	2	mA
OFFSET ADJUSTMENT RANGE		$R_F = 20\text{ k}\Omega$		± 3			± 3		mV

¹ Long-term input offset voltage stability refers to the averaged trend line of V_{OS} vs. time over extended periods after the first 30 days of operation. Excluding the initial hour of operation, changes in V_{OS} during the first 30 operating days are typically less than $2.0\ \mu\text{V}$.

² Sample tested.

³ Guaranteed by design.

⁴ Guaranteed by CMRR test condition.

⁵ To ensure high open-loop gain throughout the $\pm 10\text{ V}$ output range, A_{VO} is tested at $-10\text{ V} \leq V_O \leq 0\text{ V}$, $0\text{ V} \leq V_O \leq +10\text{ V}$, and $-10\text{ V} \leq V_O \leq +10\text{ V}$.

At $V_S = \pm 15\text{ V}$, $-40^\circ\text{C} \leq T_A \leq +85^\circ\text{C}$, unless otherwise noted.

Table 2.

Parameter	Symbol	Test Conditions/Comments	OP177F			OP177G			Unit
			Min	Typ	Max	Min	Typ	Max	
INPUT									
Input Offset Voltage	V_{OS}			15	40		20	100	μV
Average Input Offset Voltage Drift ¹	TCV_{OS}			0.1	0.3		0.7	1.2	$\mu\text{V}/^\circ\text{C}$
Input Offset Current	I_{OS}			0.5	2.2		0.5	4.5	nA
Average Input Offset Current Drift ²	TCI_{OS}			1.5	40		1.5	85	$\text{pA}/^\circ\text{C}$
Input Bias Current	I_B		-0.2	+2.4	+4		+2.4	± 6	nA
Average Input Bias Current Drift ²	TCI_B			8	40		15	60	$\text{pA}/^\circ\text{C}$
Input Voltage Range ³	IVR		± 13	± 13.5		± 13	± 13.5		V
COMMON-MODE REJECTION RATIO	CMRR	$V_{CM} = \pm 13\text{ V}$	120	140		110	140		dB
POWER SUPPLY REJECTION RATIO	PSRR	$V_S = \pm 3\text{ V to } \pm 18\text{ V}$	110	120		106	115		dB
LARGE-SIGNAL VOLTAGE GAIN ⁴	A_{VO}	$R_L \geq 2\text{ k}\Omega, V_O = \pm 10\text{ V}$	2000	6000		1000	4000		V/mV
OUTPUT VOLTAGE SWING	V_O	$R_L \geq 2\text{ k}\Omega$	± 12	± 13		± 12	± 13		V
POWER CONSUMPTION	P_D	$V_S = \pm 15\text{ V}$, no load		60	75		60	75	mW
SUPPLY CURRENT	I_{SY}	$V_S = \pm 15\text{ V}$, no load		20	2.5		2	2.5	mA

¹ TCV_{OS} is sample tested.

² Guaranteed by endpoint limits.

³ Guaranteed by CMRR test condition.

⁴ To ensure high open-loop gain throughout the $\pm 10\text{ V}$ output range, A_{VO} is tested at $-10\text{ V} \leq V_O \leq 0\text{ V}$, $0\text{ V} \leq V_O \leq +10\text{ V}$, and $-10\text{ V} \leq V_O \leq +10\text{ V}$.

TEST CIRCUITS

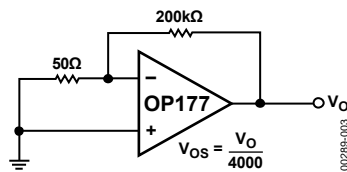


Figure 3. Typical Offset Voltage Test Circuit

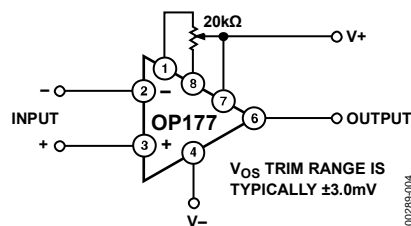


Figure 4. Optional Offset Nulling Circuit

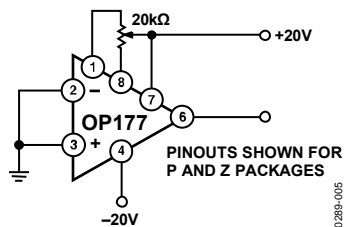


Figure 5. Burn-In Circuit

ABSOLUTE MAXIMUM RATINGS

Table 3.

Parameter	Ratings
Supply Voltage	±22 V
Internal Power Dissipation ¹	500 mW
Differential Input Voltage	±30 V
Input Voltage	±22 V
Output Short-Circuit Duration	Indefinite
Storage Temperature Range	−65°C to +125°C
Operating Temperature Range	−40°C to +85°C
Lead Temperature (Soldering, 60 sec)	300°C
DICE Junction Temperature (T _J)	−65°C to +150°C

¹ For supply voltages less than ±22 V, the absolute maximum input voltage is equal to the supply voltage.

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

THERMAL RESISTANCE

θ_{JA} is specified for worst-case mounting conditions, that is, θ_{JA} is specified for device in socket for PDIP; θ_{JA} is specified for device soldered to printed circuit board for SOIC package.

Table 4. Thermal Resistance

Package Type	θ_{JA}	θ_{JC}	Unit
8-Lead PDIP (P-Suffix)	103	43	°C/W
8-Lead SOIC (S-Suffix)	158	43	°C/W

ESD CAUTION



ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.

TYPICAL PERFORMANCE CHARACTERISTICS

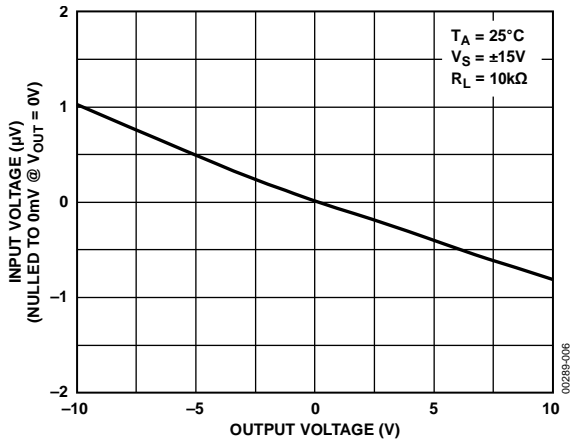


Figure 6. Gain Linearity (Input Voltage vs. Output Voltage)

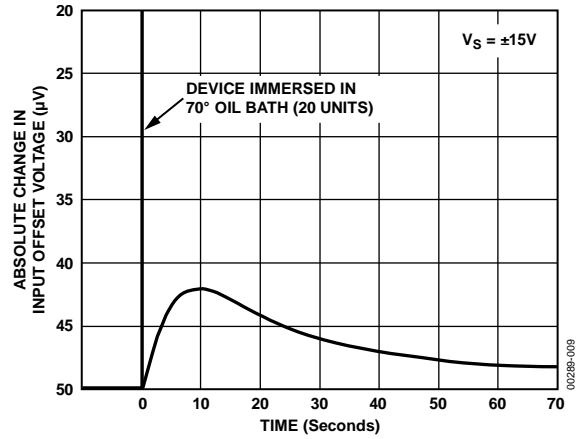


Figure 9. Offset Voltage Change Due to Thermal Shock

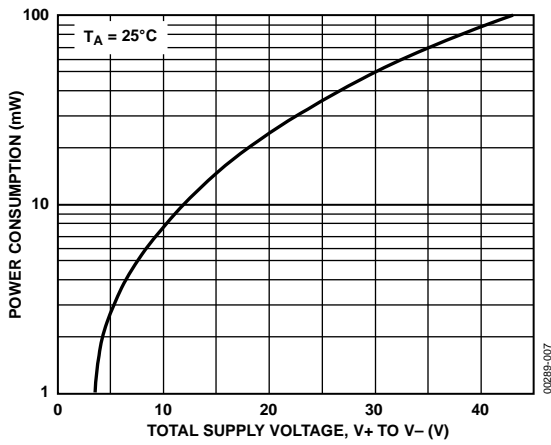


Figure 7. Power Consumption vs. Power Supply

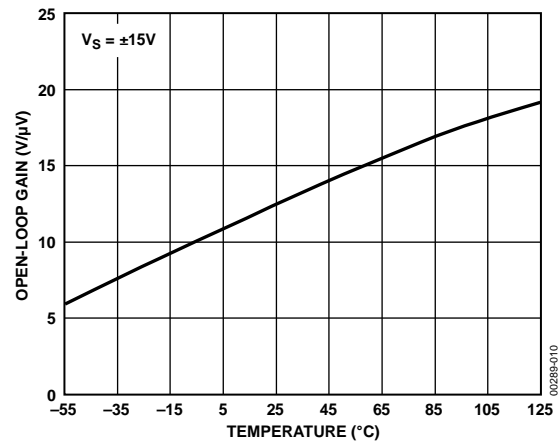


Figure 10. Open-Loop Gain vs. Temperature

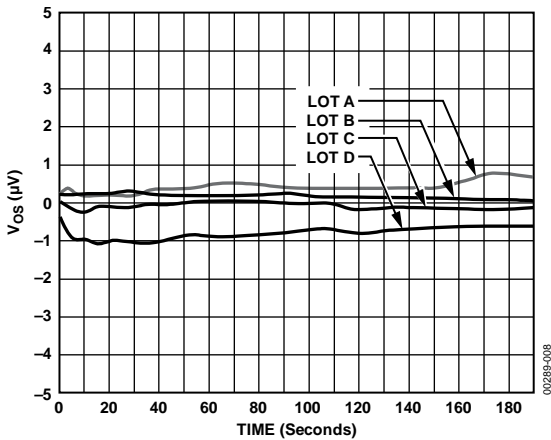


Figure 8. Warm-Up V_{OS} Drift (Normalized) Z Package

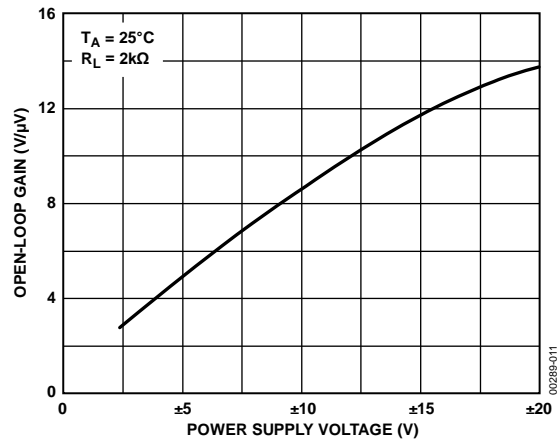


Figure 11. Open-Loop Gain vs. Power Supply Voltage

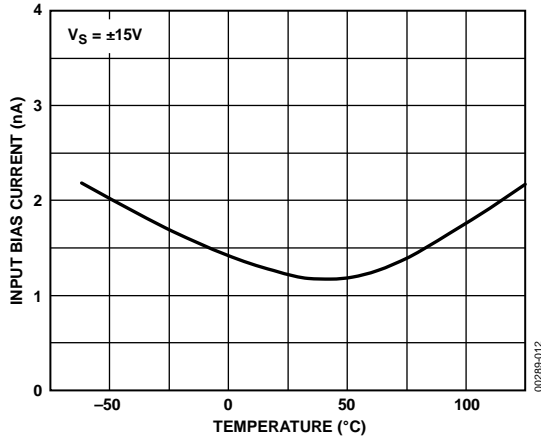


Figure 12. Input Bias Current vs. Temperature

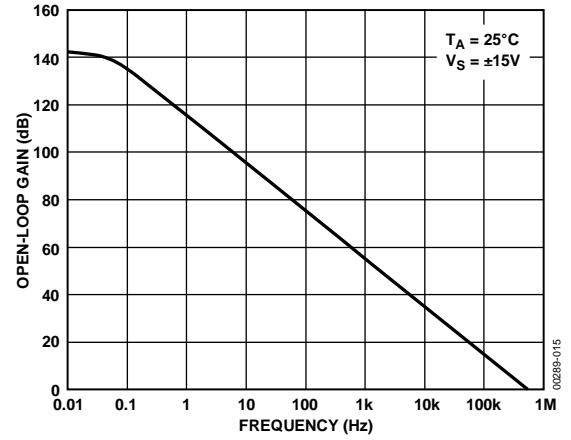


Figure 15. Open-Loop Frequency Response

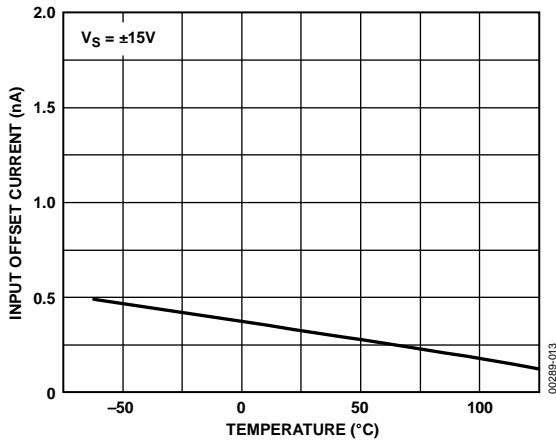


Figure 13. Input Offset Current vs. Temperature

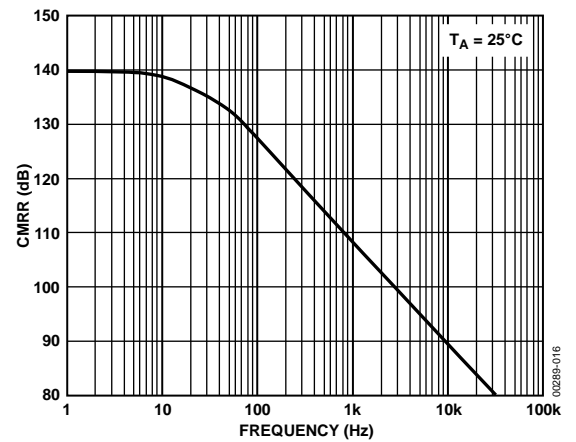


Figure 16. CMRR vs. Frequency

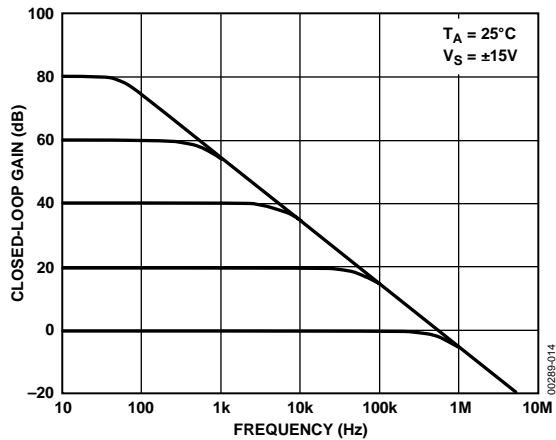


Figure 14. Closed-Loop Response for Various Gain Configurations

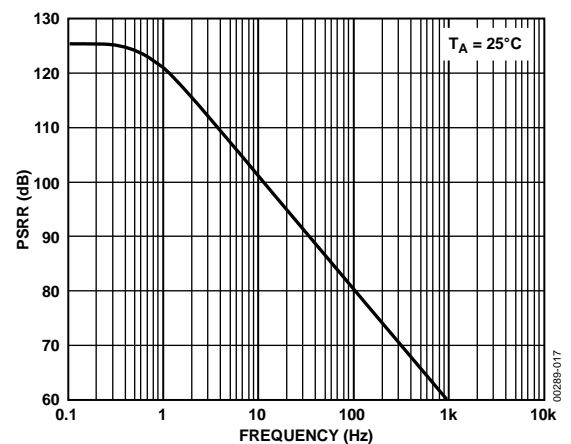


Figure 17. PSRR vs. Frequency

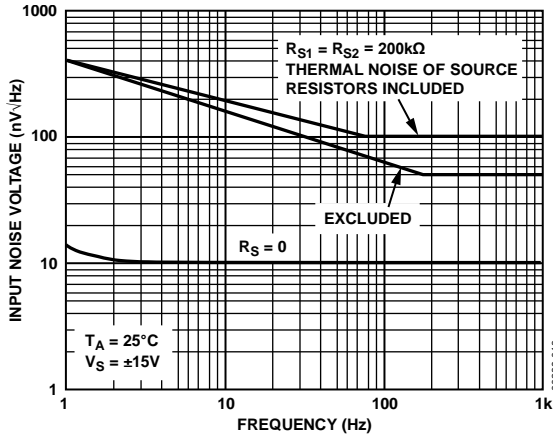


Figure 18. Total Input Noise Voltage vs. Frequency

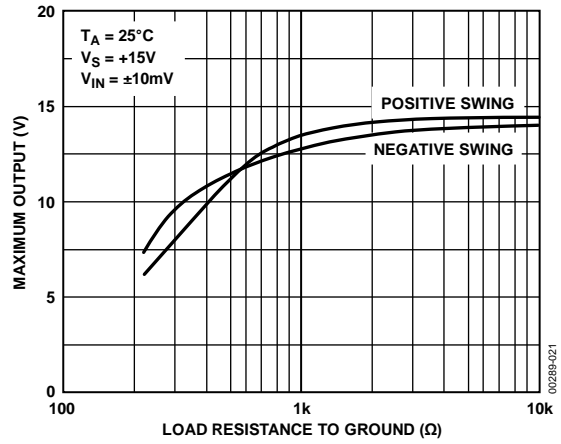


Figure 21. Maximum Output Voltage vs. Load Resistance

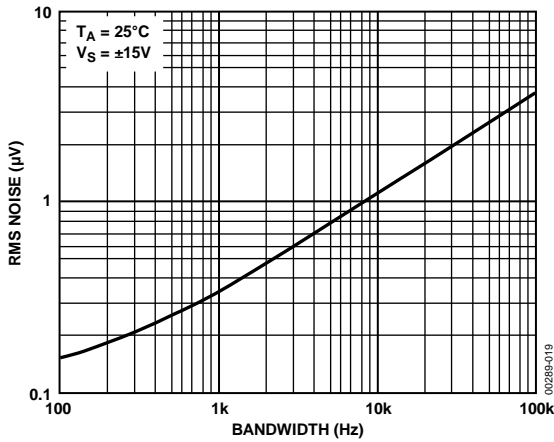


Figure 19. Input Wideband Noise vs. Bandwidth (0.1 Hz to Frequency Indicated)

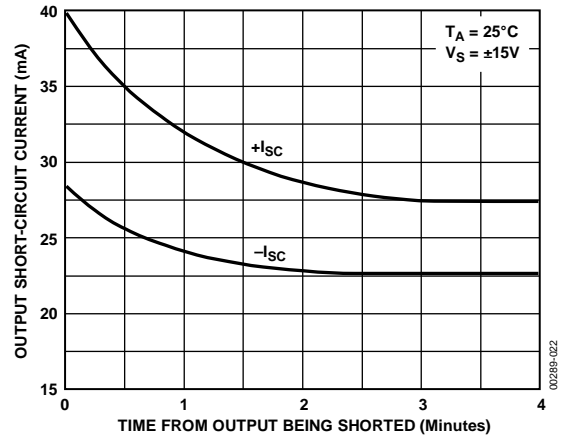


Figure 22. Output Short-Circuit Current vs. Time

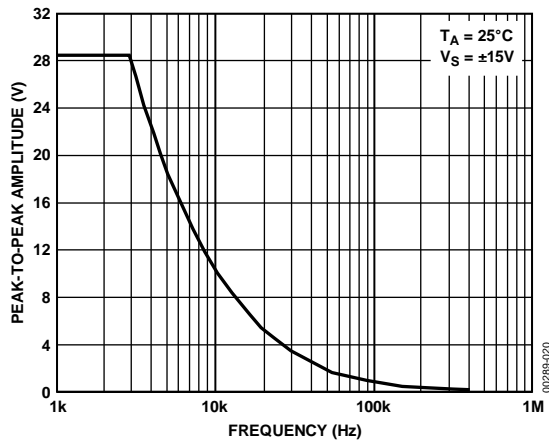


Figure 20. Maximum Output Swing vs. Frequency

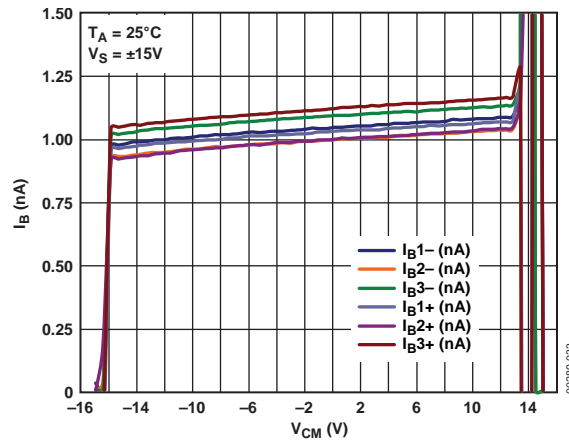


Figure 23. Input Bias (I_B) vs. Common-Mode Voltage (V_{CM})

APPLICATIONS INFORMATION

GAIN LINEARITY

The actual open-loop gain of most monolithic operational amplifiers varies at different output voltages. This nonlinearity causes errors in high closed-loop gain circuits.

It is important to know that the manufacturer's A_{VO} specification is only a part of the solution because all automated testers use endpoint testing and, therefore, show only the average gain. For example, Figure 24 shows a typical precision operational amplifier with a respectable open-loop gain of 650 V/mV. However, the gain is not constant through the output voltage range, causing nonlinear errors. An ideal operational amplifier shows a horizontal scope trace.

Figure 25 shows the **OP177** output gain linearity trace with the truly impressive average A_{VO} of 12,000 V/mV. The output trace is virtually horizontal at all points, assuring extremely high gain accuracy. Analog Devices, Inc., also performs additional testing to ensure consistent high open-loop gain at various output voltages. Figure 26 is a simple open-loop gain test circuit.

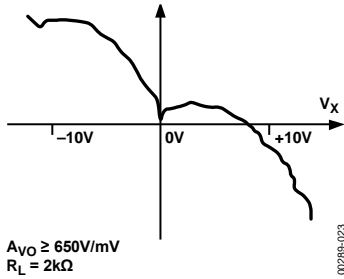


Figure 24. Typical Precision Operational amplifier

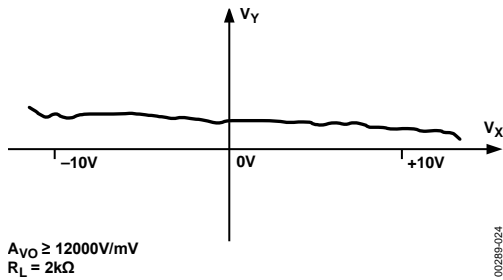


Figure 25. Output Gain Linearity Trace

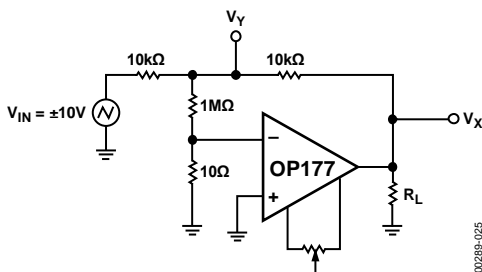


Figure 26. Open-Loop Gain Linearity Test Circuit

THERMOCOUPLE AMPLIFIER WITH COLD-JUNCTION COMPENSATION

An example of a precision circuit is a thermocouple amplifier that must accurately amplify very low level signals without introducing linearity and offset errors to the circuit. In this circuit, an S-type thermocouple with a Seebeck coefficient of $10.3 \mu\text{V}/^\circ\text{C}$ produces 10.3 mV of output voltage at a temperature of 1000°C . The amplifier gain is set at 973.16, thus, it produces an output voltage of 10.024 V. Extended temperature ranges beyond 1500°C are accomplished by reducing the amplifier gain. The circuit uses a low cost diode to sense the temperature at the terminating junctions and, in turn, compensates for any ambient temperature change. The **OP177**, with the high open-loop gain plus low offset voltage and drift, combines to yield a precise temperature sensing circuit. Circuit values for other thermocouple types are listed in Table 5.

Table 5.

Thermocouple Type	Seebeck Coefficient	R1	R2	R7	R9
K	$39.2 \mu\text{V}/^\circ\text{C}$	110Ω	$5.76 \text{ k}\Omega$	$102 \text{ k}\Omega$	$269 \text{ k}\Omega$
J	$50.2 \mu\text{V}/^\circ\text{C}$	100Ω	$4.02 \text{ k}\Omega$	$80.6 \text{ k}\Omega$	$200 \text{ k}\Omega$
S	$10.3 \mu\text{V}/^\circ\text{C}$	100Ω	$20.5 \text{ k}\Omega$	$392 \text{ k}\Omega$	$1.07 \text{ M}\Omega$

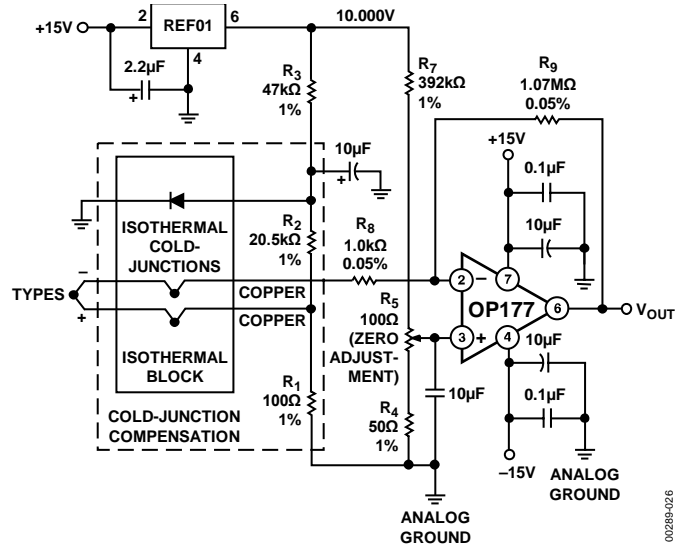


Figure 27. Thermocouple Amplifier with Cold Junction Compensation

PRECISION HIGH GAIN DIFFERENTIAL AMPLIFIER

The high gain, gain linearity, CMRR, and low TCV_{OS} of the OP177 make it possible to obtain performance not previously available in single stage, very high gain amplifier applications. See Figure 28.

For best CMR, $\frac{R1}{R2}$ must equal $\frac{R3}{R4}$

In this example, with a 10 mV differential signal, the maximum errors are listed in Table 6.

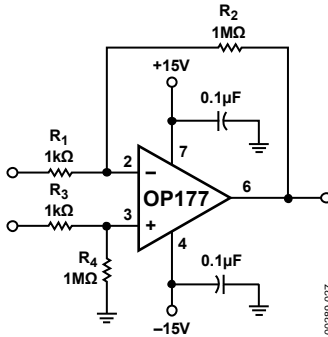


Figure 28. Precision High Gain Differential Amplifier

Table 6. High Gain Differential Amplifier Performance

Type	Amount
Common-Mode Voltage	0.1%/V
Gain Linearity, Worst Case	0.02%
TCV _{OS}	0.0003%/°C
TCl _{OS}	0.008%/°C

ISOLATING LARGE CAPACITIVE LOADS

The circuit shown in Figure 29 reduces maximum slew rate but allows driving capacitive loads of any size without instability. Because the 100 Ω resistor is inside the feedback loop, the effect on output impedance is reduced to insignificance by the high open loop gain of the OP177.

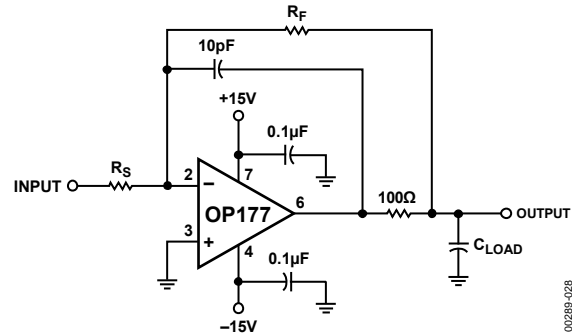


Figure 29. Isolating Capacitive Loads

BILATERAL CURRENT SOURCE

The current sources shown in Figure 30 supply both positive and negative currents into a grounded load.

Note that

$$Z_o = \frac{R5 \left(\frac{R4}{R2} + 1 \right)}{\frac{R5 + R4}{R2} - \frac{R3}{R1}}$$

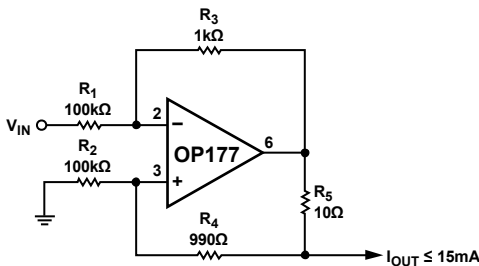
and that for Z_o to be infinite

$$\frac{R5 + R4}{R2} \text{ must} = \frac{R3}{R1}$$

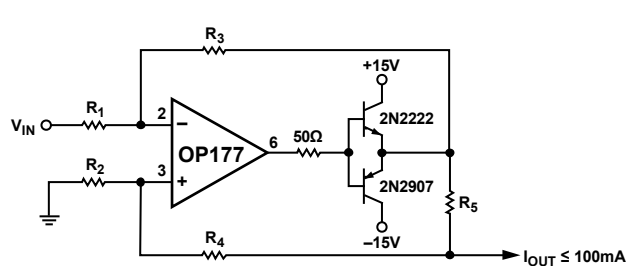
PRECISION ABSOLUTE VALUE AMPLIFIER

The high gain and low TCV_{OS} assure accurate operation with inputs from microvolts to volts. In this circuit, the signal always appears as a common-mode signal to the operational amplifiers (for details, see Figure 31).

BASIC CURRENT SOURCE



100mA CURRENT SOURCE



$$I_{OUT} = V_{IN} \frac{R3}{R1 \times R5}$$

GIVEN R₃ = R₄ + R₅, R₁ = R₂

Figure 30. Bilateral Current Source

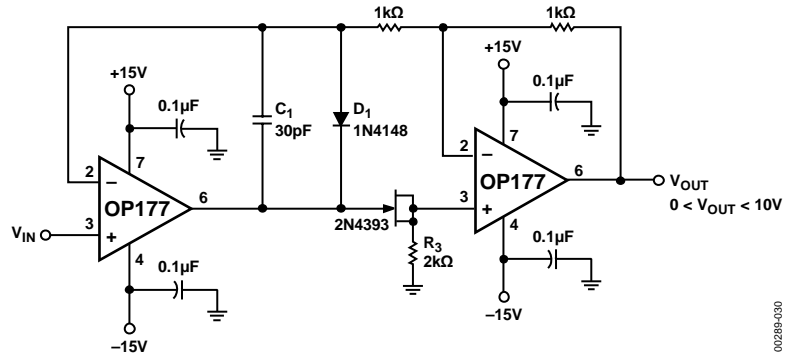


Figure 31. Precision Absolute Value Amplifier

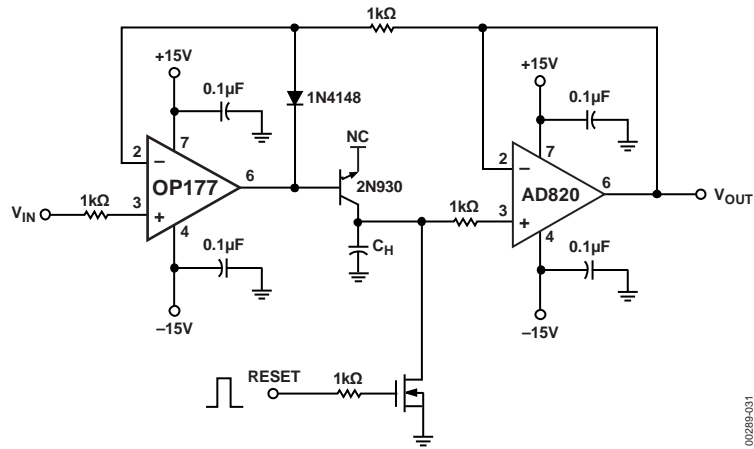


Figure 32. Precision Positive Peak Detector

PRECISION POSITIVE PEAK DETECTOR

In Figure 32, C_H must be polystyrene, Teflon®, or polyethylene to minimize dielectric absorption and leakage. The droop rate is determined by the size of C_H and the bias current of the AD820.

PRECISION THRESHOLD DETECTOR/AMPLIFIER

In Figure 33, when $V_{IN} < V_{TH}$, amplifier output swings negative, reverse biasing diode D_1 . $V_{OUT} = V_{TH}$ if $R_L = \infty$. When $V_{IN} \geq V_{TH}$, the loop closes.

$$V_{OUT} = V_{TH} + (V_{IN} - V_{TH}) \left(1 + \frac{R_F}{R_S} \right)$$

C_C is selected to smooth the response of the loop.

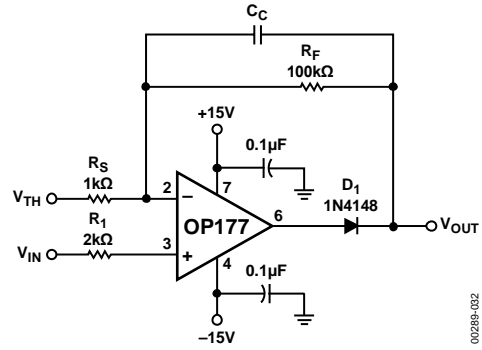
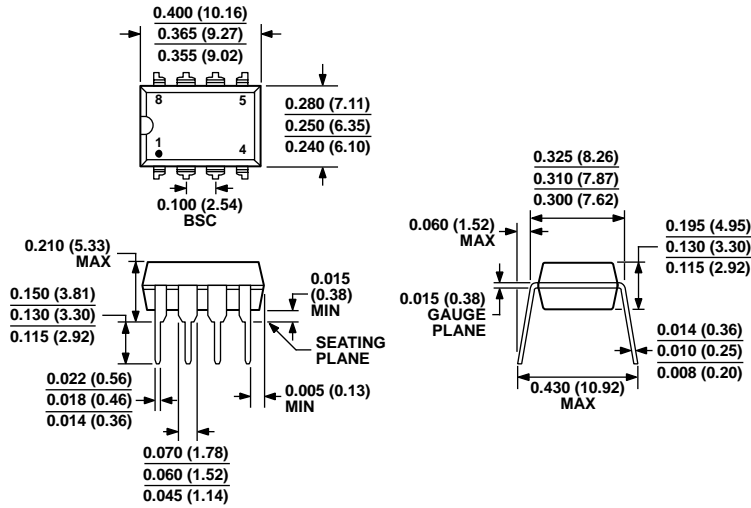


Figure 33. Precision Threshold Detector/Amplifier

010289-082

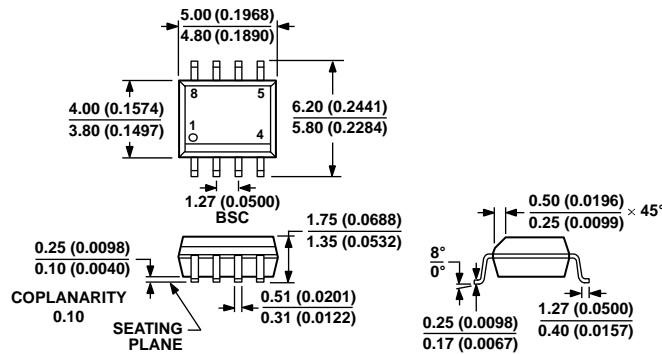
OUTLINE DIMENSIONS



COMPLIANT TO JEDEC STANDARDS MS-001
 CONTROLLING DIMENSIONS ARE IN INCHES; MILLIMETER DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF INCH EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN. CORNER LEADS MAY BE CONFIGURED AS WHOLE OR HALF LEADS.

Figure 34. 8-Lead Plastic Dual In-Line Package (PDIP)
 P-Suffix
 (N-8)

Dimensions show in inches and (millimeters)



COMPLIANT TO JEDEC STANDARDS MS-012-AA
 CONTROLLING DIMENSIONS ARE IN MILLIMETERS; INCH DIMENSIONS (IN PARENTHESES) ARE ROUNDED-OFF MILLIMETER EQUIVALENTS FOR REFERENCE ONLY AND ARE NOT APPROPRIATE FOR USE IN DESIGN.

Figure 35. 8-Lead Standard Small Outline Package (SOIC_N)
 S-Suffix
 (R-8)

Dimensions shown in millimeters and (inches)

ORDERING GUIDE

Model ¹	Temperature Range	Package Description	Package Option
OP177FPZ	-40°C to +85°C	8-Lead PDIP	P-Suffix (N-8)
OP177GPZ	-40°C to +85°C	8-Lead PDIP	P-Suffix (N-8)
OP177FSZ	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177FSZ-REEL	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177FSZ-REEL7	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177GS	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177GS-REEL	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177GS-REEL7	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177GSZ	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177GSZ-REEL	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)
OP177GSZ-REEL7	-40°C to +85°C	8-Lead SOIC_N	S-Suffix (R-8)

¹ Z = RoHS Compliant Part.

NOTES

NOTES

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[OP177GPZ](#) [OP177GS-REEL7](#) [OP177GSZ-REEL](#) [OP177GS-REEL](#)